

Search Notes

Application/Control No.

09/673,422

Examiner

Christopher A. Revak

Applicant(s)/Patent under
Reexamination

TAKECHI ET AL.

Art Unit

2131

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 713 | 158,194 | 9/12/2006 | CR |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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| 709 | 217,229 | 4/2/2004 | CR |
| 382 | 100 | 4/2/2004 | CR |
| 705 | 52,54,59 | 4/2/2004 | CR |
| 713/155,165,175,176, 190,193,200 | | 4/2/2004 | CR |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| BRS Text Search USPAT, US PGPUB, USOCR, DERWENT, IBM TDB, FPRS, EPO, JPO | 9/12/2006 | CR |
| DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE | 9/12/2006 | CR |
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Search Notes (continued)

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2131

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|-------|----------|-----------|----------|
| none | none | 9/12/2006 | CR |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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| 725 | 29 | 4/2/2004 | CR |
| 713 | 158,194 | 9/12/2006 | CR |
| 380/28,100,242,255,283 | | 4/2/2004 | CR |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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